

# **Cypress Semiconductor Package Qualification Report**

**QTP# 034706 VERSION 1.0  
December, 2003**

**48-lead Thin Small Outline Package (TSOP),  
(12 x 20 x 1.2mm)  
235°C Reflow, MSL3  
OSE-Taiwan**

## **CYPRESS TECHNICAL CONTACT FOR QUALIFICATION DATA:**

Rene Rodgers  
Staff Reliability Engineer  
(408 943-2732)

### PACKAGE QUALIFICATION HISTORY

<b>Qual Report</b>	<b>Description of Qualification Purpose</b>	<b>Date Comp</b>
034706	48-lead TSOP (12 x 20 x 1.2mm) package, assembled at OSE-Taiwan, @235°C Reflow, MSL3	Dec 03

<b>MAJOR PACKAGE INFORMATION USED IN THIS QUALIFICATION</b>	
<b>Package Designation:</b>	Z48A
<b>Package Outline, Type, or Name:</b>	48-lead Thin Small Outline Package (TSOP)
<b>Mold Compound Name/Manufacturer:</b>	Sumitomo 7351LS
<b>Mold Compound Flammability Rating:</b>	V-O per UL94
<b>Oxygen Rating Index:</b>	>28%
<b>Lead Frame Material:</b>	Copper
<b>Lead Finish, Composition / Thickness:</b>	Solder Plated 85% +10/-5Sn, 15% +5/-10Pb
<b>Die Backside Preparation Method/Metallization:</b>	Grinding
<b>Die Separation Method:</b>	Sawing
<b>Die Attach Supplier:</b>	Ablestik
<b>Die Attach Material:</b>	Ablebond 8340
<b>Die Attach Method:</b>	Dispensing
<b>Bond Diagram Designation</b>	10-05183
<b>Wire Bond Method:</b>	Thermosonic
<b>Wire Material/Size:</b>	Au, 1.0mil
<b>Thermal Resistance Theta JA °C/W:</b>	35.85°C/W
<b>Package Cross Section Yes/No:</b>	N/A
<b>Assembly Process Flow:</b>	49-35006
<b>Name/Location of Assembly (prime) facility:</b>	OSE-Taiwan

### PACKAGE AVAILABILITY

PACKAGE	ASSEMBLY SITE FACILITY
48-lead TSOP	OSE-Taiwan

**RELIABILITY TESTS PERFORMED PER SPECIFICATION REQUIREMENT**

<b>Stress/Test</b>	<b>Test Condition (Temp/Bias)</b>	<b>Result P/F</b>
Temperature Cycle	Precondition: JESD22 Moisture Sensitivity MSL 3 192 Hrs., 30°C/60%RH+3IR-Reflow, 235°C+5, 0°C MIL-STD-883C, Method 1010, Condition C, -65°C to 150°C	P
Pressure Cooker	Precondition: JESD22 Moisture Sensitivity MSL 3 192 Hrs., 30°C/60%RH+3IR-Reflow, 235°C+5, -0°C 121°C, 100%RH	P
High Accelerated Saturation Test (HAST)	130°C, 3.6V, 85%RH Precondition: JESD22 Moisture Sensitivity MSL 3 192 Hrs, 85C/85%RH+3IR-Reflow, 235°C+5, 0°C	P
Electrostatic Discharge Charge Device Model (ESD-CDM)	500V Cypress Spec. 25-00020	P
Electrostatic Discharge Human Body Model (ESD-HBM)	2,200V MIL-STD-883, Method 3015.7	P
High Temperature Storage	150°C, no bias	P
Thermal Shock	-55C to +125C Cypress Spec. 25-00014	P
Physical Dimensions	Cypress Spec 25-00031	P
Ball Shear	Cypress Spec 12-00292	P
Die Shear	Cypress Spec 12-00292	P
External Visual	Cypress Spec 12-00292	P
Internal Visual	Cypress Spec 12-00292	P
Solderability	Cypress Spec 12-00292	P
X-ray	MIL-STD-883C, Method 2012, Cypress Spec 12-00292	P
Acoustic Microscopy MSL3	Cypress Spec 12-00292	

## Reliability Test Data

QTP #: 034706

<b>Device</b>	<b>Fab Lot #</b>	<b>Assy Lot #</b>	<b>Assy Loc</b>	<b>Duration</b>	<b>Samp</b>	<b>Rej</b>	<b>Failure Mechanism</b>
<b>STRESS: ACOUSTIC-MSL3</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	15	0	
CY62167DV30LL	4318891	610330005	TAIWN-T	COMP	15	0	
CY62167DV30LL	4318891	610330006	TAIWN-T	COMP	15	0	
<b>STRESS : INTERNAL VISUAL</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	5	0	
<b>STRESS : EXTERNAL VISUAL</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	15	0	
<b>STRESS: PHYSICAL DIMENSION</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	5	0	
<b>STRESS: BALL SHEAR</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	10	0	
<b>STRESS: DIE SHEAR</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	15	0	
<b>STRESS: X-RAY</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	15	0	
<b>STRESS: SOLDERABILITY</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	COMP	3	0	
<b>STRESS: THERMAL SHOCK, 125C, -55C</b>							
CY62167DV30LL	4319109	610340080	TAIWN-T	100	50	0	
CY62167DV30LL	4319109	610340080	TAIWN-T	200	50	0	
<b>STRESS: ESD-HUMAN BODY CIRCUIT PER MIL STD 883, METHOD 3015, 2,200V</b>							
CY62167DV30LL	4318891	610330005	TAIWN-T	COMP	9	0	
<b>STRESS: ESD-CHARGE DEVICE MODEL, 500V</b>							
CY62167DV30LL	4318891	610330005	TAIWN-T	COMP	9	0	

## Reliability Test Data

QTP #: 034706

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
<b>STRESS: HIGH TEMPERATURE STORAGE, 150C</b>							
CY62167DV30LL	4314972	610330190	TAIWN-T	500	43	0	
CY62167DV30LL	4314972	610330190	TAIWN-T	1000	43	0	
<b>STRESS: PRESSURE COOKER TEST, 121C, 100%RH, PRE COND 192 HR 30C/60%RH, MSL3</b>							
CY62167DV30LL	4318891	610330006	TAIWN-T	168	44	0	
<b>STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 3.6V), PRE COND 192 HR 30C/60%RH, MSL3</b>							
CY62167DV30LL	4318891	610330007	TAIWN-T	128	43	0	
<b>STRESS: TC COND. C -65C TO 150C, PRECONDITION 192 HRS 30C/60%RH, MSL3</b>							
CY62167DV30LL	4319109	610339693	TAIWN-T	300	44	0	
CY62167DV30LL	4319109	610339693	TAIWN-T	500	44	0	
CY62167DV30LL	4319109	610339695	TAIWN-T	300	49	0	
CY62167DV30LL	4319109	610339695	TAIWN-T	500	49	0	
CY62167DV30LL	4319109	610340080	TAIWN-T	300	48	0	
CY62167DV30LL	4319109	610340080	TAIWN-T	500	48	0	